

Application/Contro	ol No.	Applicant(s)/Patent under Reexamination	
09/726,822		GUITER ET AL	
Examiner		Art Unit	
Shin-Hon Chen		2131	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT, PGPUB, EPO, JPO, DERWENT (BRS Search)	5/23/2006	S.C.	